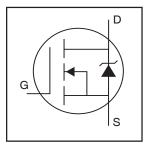
International Rectifier

IRFZ46NPbF

HEXFET® Power MOSFET

- Advanced Process Technology
- Ultra Low On-Resistance
- Dynamic dv/dt Rating
- 175°C Operating Temperature
- Fast Switching
- Fully Avalanche Rated
- Lead-Free



$$V_{DSS} = 55V$$
 $R_{DS(on)} = 16.5 m\Omega$
 $I_D = 53 A^{\circ}$

Description

Advanced HEXFET® Power MOSFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 watts. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.



Absolute Maximum Ratings

	Parameter	Max.	Units
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V	53⑦	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	37	A
I _{DM}	Pulsed Drain Current ①	180	
P _D @T _C = 25°C	Power Dissipation	107	W
	Linear Derating Factor	0.71	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
I _{AR}	Avalanche Current ①	28	A
E _{AR}	Repetitive Avalanche Energy ①	11	mJ
dv/dt	Peak Diode Recovery dv/dt 3	5.0	V/ns
T _J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 srew	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-Case	_	1.4	
R _{θCS}	Case-to-Sink, Flat, Greased Surface	0.50		°C/W
$R_{\theta JA}$	Junction-to-Ambient		62	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
Breakdown Voltage Temp. Coefficient		0.057		V/°C	Reference to 25°C, I _D = 1mA
Static Drain-to-Source On-Resistance			16.5	mΩ	V _{GS} = 10V, I _D = 28A ④
Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$
Forward Transconductance	19			S	V _{DS} = 25V, I _D = 28A⊕
Drain-to-Source Leakage Current			25		$V_{DS} = 55V, V_{GS} = 0V$
Dialii-to-Source Leakage Ourient			250	μΑ	V _{DS} = 44V, V _{GS} = 0V, T _J = 150°C
Gate-to-Source Forward Leakage			100	nΛ	V _{GS} = 20V
Gate-to-Source Reverse Leakage			-100	l IIA	V _{GS} = -20V
Total Gate Charge			72		I _D = 28A
Gate-to-Source Charge			11	nC	$V_{DS} = 44V$
Gate-to-Drain ("Miller") Charge			26		$V_{GS} = 10V$, See Fig. 6 and 13
Turn-On Delay Time		14			$V_{DD} = 28V$
Rise Time		76		200	$I_D = 28A$
Turn-Off Delay Time		52		- IIS	$R_G = 12\Omega$
Fall Time		57			V _{GS} = 10V, See Fig. 10 ④
Internal Drain Industrance		15			Between lead,
memai Diam inductance		4.5		- LU	6mm (0.25in.)
Internal Course Industria					from package
Internal Source Inductance		7.5			and center of die contact
Input Capacitance		1696			$V_{GS} = 0V$
Output Capacitance		407			$V_{DS} = 25V$
Reverse Transfer Capacitance		110		pF	f = 1.0MHz, See Fig. 5
Single Pulse Avalanche Energy 2		583⑤	152©	mJ	I _{AS} = 28A, L = 389μH
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Input Capacitance Output Capacitance Reverse Transfer Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Internal Drain Inductance Input Capacitance Output Capacitance Reverse Transfer Capacitance ———————————————————————————————————	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Forward Transconductance Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Total Gate Charge Gate-to-Drain ("Miller") Charge Turn-On Delay Time Time Time Time Toff Delay Time Fall Time Fall Time Fall Time Formard Transconductance Forward Leakage Forward TransforGalagae Forward	Drain-to-Source Breakdown Voltage 55 — Breakdown Voltage Temp. Coefficient — 0.057 — Static Drain-to-Source On-Resistance — 16.5 Gate Threshold Voltage 2.0 — 4.0 Forward Transconductance 19 — — Drain-to-Source Leakage Current — 25 — — 25 Gate-to-Source Leakage Current — — 25 — — 25 Gate-to-Source Forward Leakage — — 100 — — 25 Gate-to-Source Reverse Leakage — — 72 — — 72 — — 72 — — — 72 — — — — — — 72 —	Drain-to-Source Breakdown Voltage 55 — V Breakdown Voltage Temp. Coefficient — 0.057 — V/°C Static Drain-to-Source On-Resistance — — 16.5 mΩ Gate Threshold Voltage 2.0 — 4.0 V Forward Transconductance 19 — — S Drain-to-Source Leakage Current — — 25 μA Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Forward Leakage — — 100 nA Total Gate Charge — — 100 nA Gate-to-Source Reverse Leakage — — 72 nC Gate-to-Source Charge — — 11 nC Gate-to-Drain ("Miller") Charge — — 26 Turn-On Delay Time — 14 — Rise Time — 52 — Internal Drain Inductance — 4.5 —

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions		
Is	Continuous Source Current			53		MOSFET symbol		
	(Body Diode)	53		Α	showing the			
I _{SM}	Pulsed Source Current			100	180	integral reverse		
	(Body Diode)①			180		p-n junction diode.		
V _{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C$, $I_S = 28A$, $V_{GS} = 0V$ ④		
t _{rr}	Reverse Recovery Time		67	101	ns	$T_J = 25^{\circ}C$, $I_F = 28A$		
Q _{rr}	Reverse Recovery Charge	_	208	312	nC	di/dt = 100A/μs ④		
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by L _S +L _D)						

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11).
- $$\label{eq:starting} \begin{split} \text{\textcircled{2}} \quad & \text{Starting T}_J = 25^{\circ}\text{C}, \, L = 389 \mu\text{H} \\ & \text{R}_G = 25 \Omega, \, I_{AS} = 28 \text{A}. \, \text{(See Figure 12)}. \end{split}$$
- $\label{eq:loss} \begin{array}{l} \text{ } \mathbb{J}_{SD} \leq 28\text{A}, \text{ di/dt} \leq 220\text{A/}\mu\text{s}, \text{ } V_{DD} \leq V_{(BR)DSS}, \\ T_{J} \leq 175^{\circ}\text{C}. \end{array}$
- 4 Pulse width $\leq 400 \mu s$; duty cycle $\leq 2\%$.
- ⑤ This is a typical value at device destruction and represents operation outside rated limits.
- 6 This is a calculated value limited to $T_J = 175^{\circ}C$.
- ② Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 39A.

International TOR Rectifier

IRFZ46NPbF

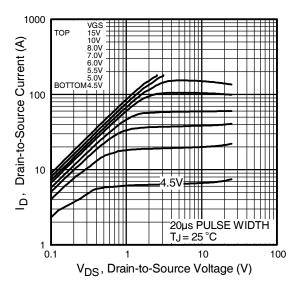


Fig 1. Typical Output Characteristics

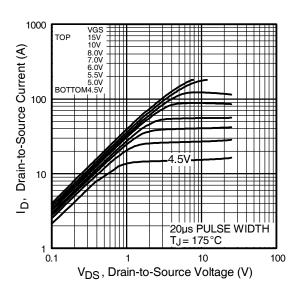


Fig 2. Typical Output Characteristics

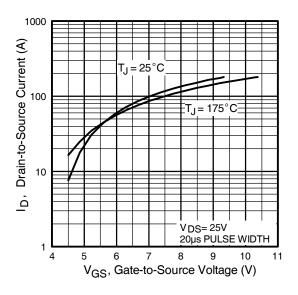


Fig 3. Typical Transfer Characteristics

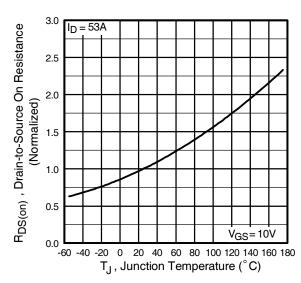


Fig 4. Normalized On-Resistance Vs. Temperature

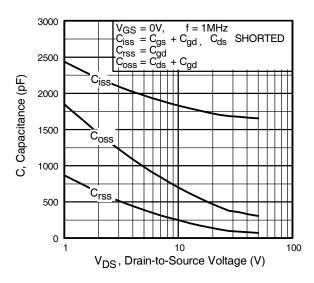


Fig 5. Typical Capacitance Vs. Drain-to-Source Voltage

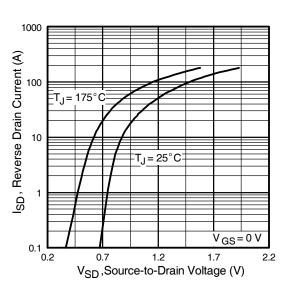


Fig 7. Typical Source-Drain Diode Forward Voltage

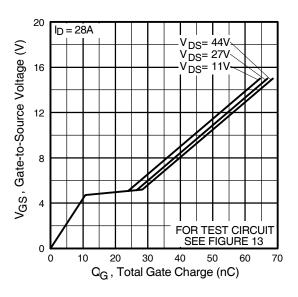


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

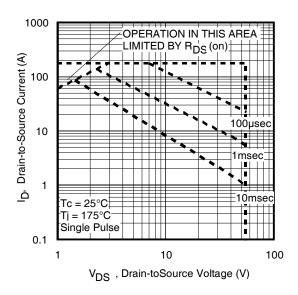


Fig 8. Maximum Safe Operating Area

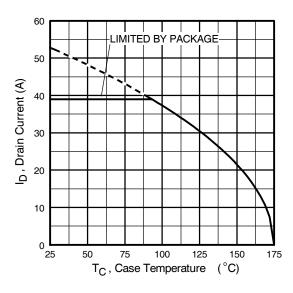


Fig 9. Maximum Drain Current Vs. Case Temperature

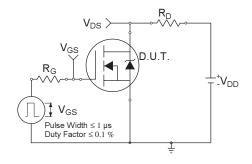


Fig 10a. Switching Time Test Circuit

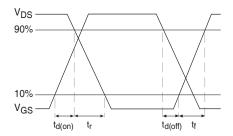


Fig 10b. Switching Time Waveforms

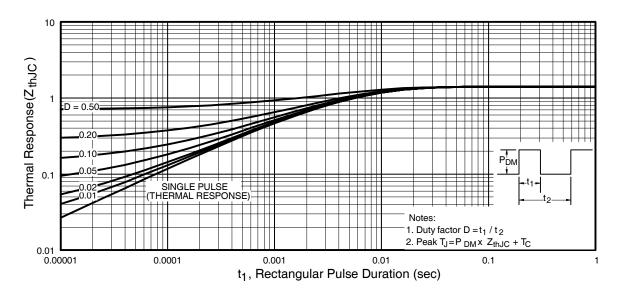


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

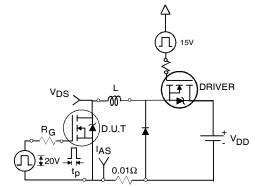


Fig 12a. Unclamped Inductive Test Circuit

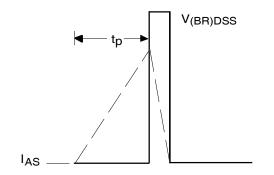


Fig 12b. Unclamped Inductive Waveforms

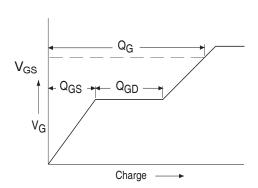


Fig 13a. Basic Gate Charge Waveform

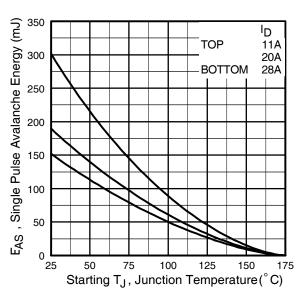


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

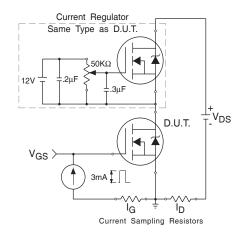
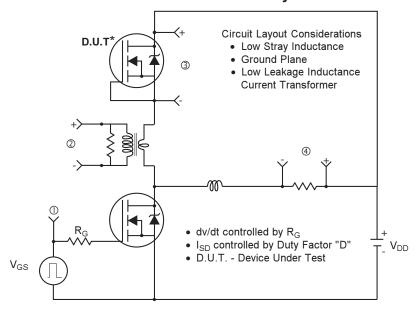
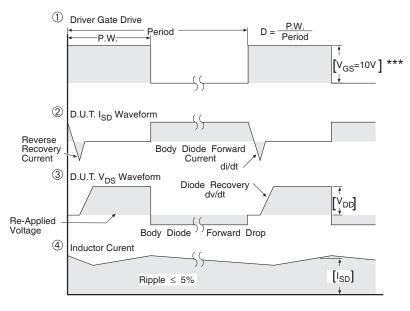


Fig 13b. Gate Charge Test Circuit

Peak Diode Recovery dv/dt Test Circuit



* Reverse Polarity of D.U.T for P-Channel



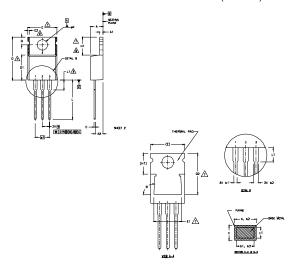
*** V_{GS} = 5.0V for Logic Level and 3V Drive Devices

Fig 14. For N-channel HEXFET® power MOSFETs

International IOR Rectifier

TO-220AB Package Outline

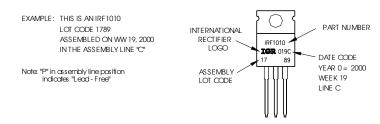
Dimensions are shown in millimeters (inches)



NOTE 1 2 3 4 5 6 7 8	DIMENSIO DIMENSIO DIMENSIO SHALL IN MEASURI DIMENSIO THERMAL DIMENSIO DIMENSIO DIMENSIO	SUMENSIONING AND TOLERANCING PER ASME Y14.5 M - 1994. DMENSIONIS ARE SHORN IN INCHES [MILLIMETERS]. LEAD DMENSION AS ENOUGH IN INCHES [MILLIMETERS]. LEAD DMENSION D. & E.D ONT INCLUE WOLD FRASH. MAD FLASH SHALL NOT EXCEED 005" (0.127) PER SIDE. THESE DMENSIONS ARE MEASURED AT HE CUPRINGES TERRESS OF THE PLASTIC BODY. DMENSION D. & C.I. POPLY TO BESE METAL ONLY. CONTROLLING DMENSION: MONES. THERMAL PIAD CONTROL POPLONAL WITHIN DMENSIONS E,H1.02 & E1 DMENSION LEX. X-HI DEFINE A ZONE MHERE STAMPING AND SINGLALIDMENT REPOLABITIES ARE ALLOYED.							
	SYMBOL	3.— EMITTER <u>DKODES</u> 1.— ANODE/OPEI							
		MIN.	leters Max.	Min,	MAX,	NOTES	2,- CATHODE 3,- ANODE		
	A	3,56	4.82	.140	.190				
	A1	0.51	1,40	.020	.055				
	42	2.04	1 202	000	115				

SYMBOL	MILLIMETERS		INC		
	Min.	MAX.	MiN.	MAX,	NOTES
A	3,56	4.82	,140	.190	
A1	0,51	1,40	.020	.055	
A2	2,04	2,92	.080	,115	
b	0.38	1,01	.015	.040	
ь1	0.38	0.96	.015	.03B	5
b2	1.15	1,77	.045	.070	
b3	1.15	1,73	.045	.068	
c	0.36	0,61	,014	.024	
c1	0.36	0,56	,014	.022	5
D	14,22	15.51	.560	.650	4
D1	8.38	9.02	.330	.355	
D2	12,19	12.88	.480	.507	7
E	9,66	10.66	,380	.420	4,7
E1	8,38	8,89	,330	,350 BSC	7
е	2.54 BSC		,100		
e1	5.08		.200 BSC		
H1	5.85	6.55	.230	.270	7,8
L	12.70	14.73	.500	.580	
L1	-	6.35	-	.250	3
øΡ	3,54	4,08	,139	.161	
Q	2.54	3.42	.100	.135	
0	90'-	-93*	90*-		

TO-220AB Part Marking Information



Notes:

- 1. For an Automotive Qualified version of this part please seehttp://www.irf.com/product-info/auto/
- 2. For the most current drawing please refer to IR website at http://www.irf.com/package/

Data and specifications subject to change without notice. This product has been designed and qualified for the Industrial market. Qualification Standards can be found on IR's Web site.



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